

Search Notes**Application/Control No.**

10/713,468

Examiner

Hai L. Nguyen

Applicant(s)/Patent under Reexamination

KNIERIM ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
331	16,18,25, 1A,1R, DIG.2	4/20/2005	HLN
327	47,115		
	117,147		
	156,167		
	291		
375	373,375	4/21/2005	
	376		
377	48		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	4/25/2005	HLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner